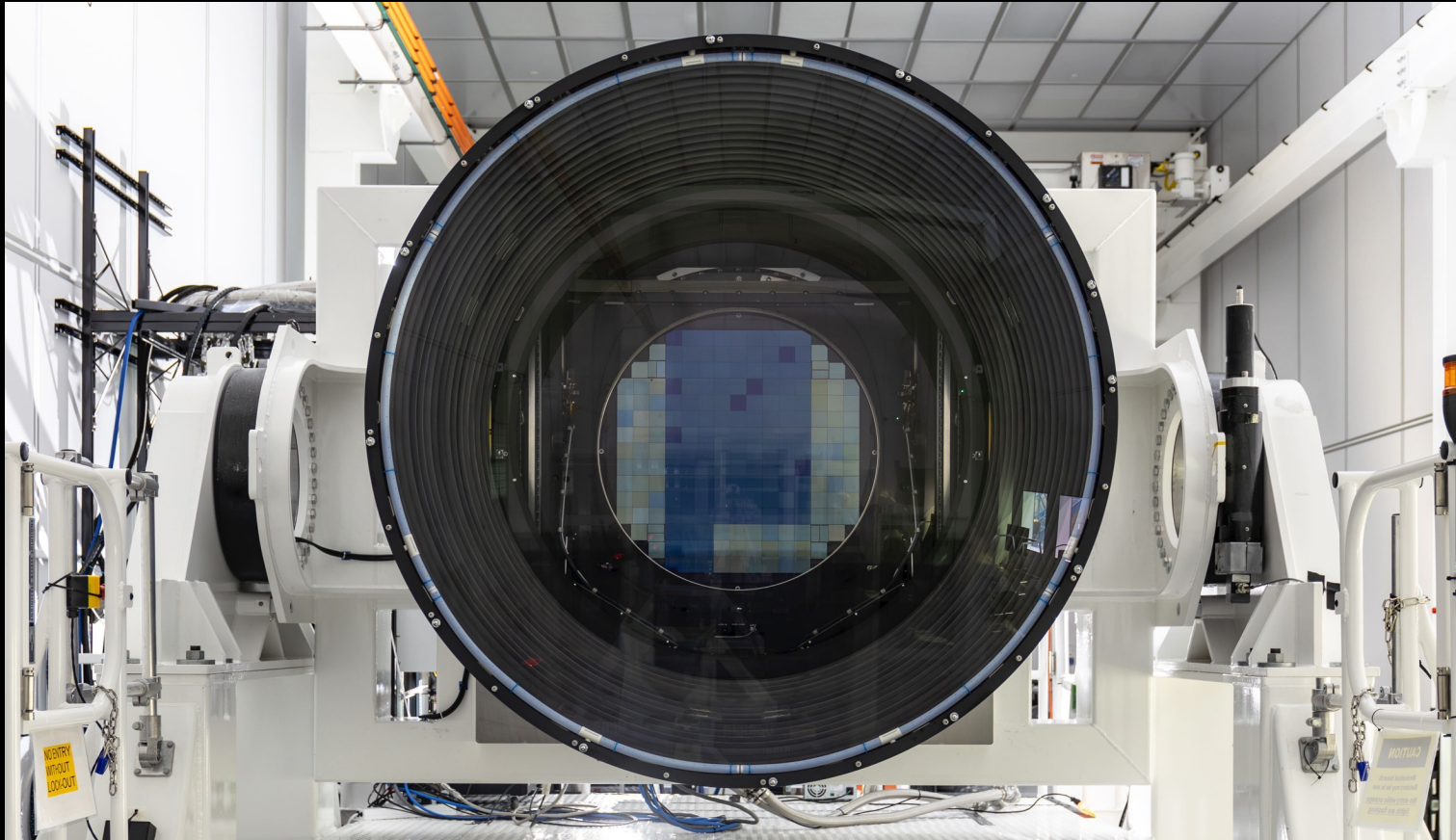


# LSST CCDs anomalies

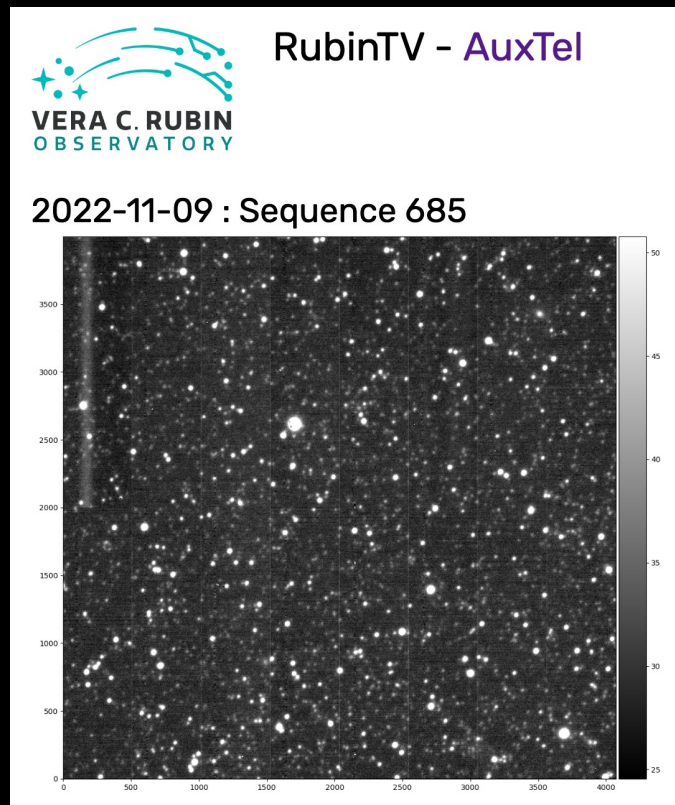
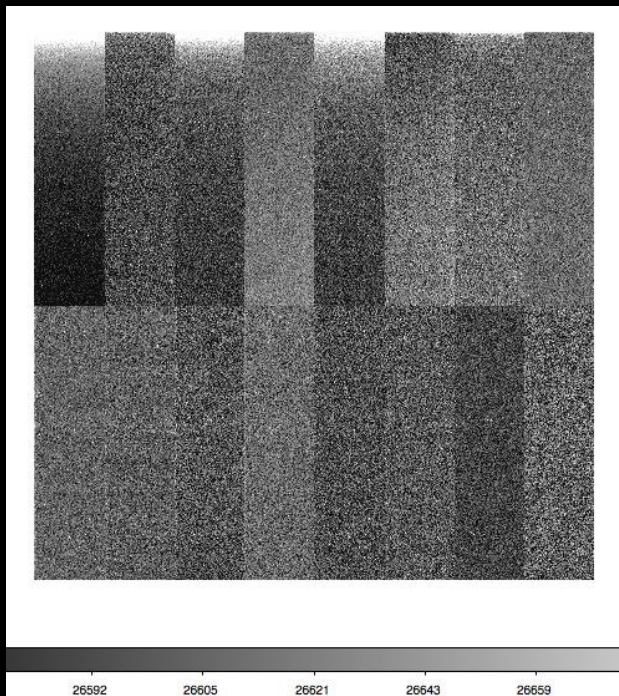


Claire Juramy

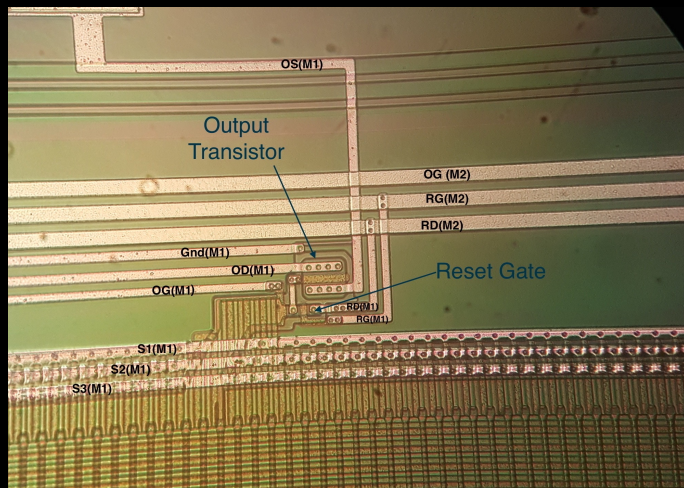
LSST-France commissioning – 27/03/2024

# Bias stability

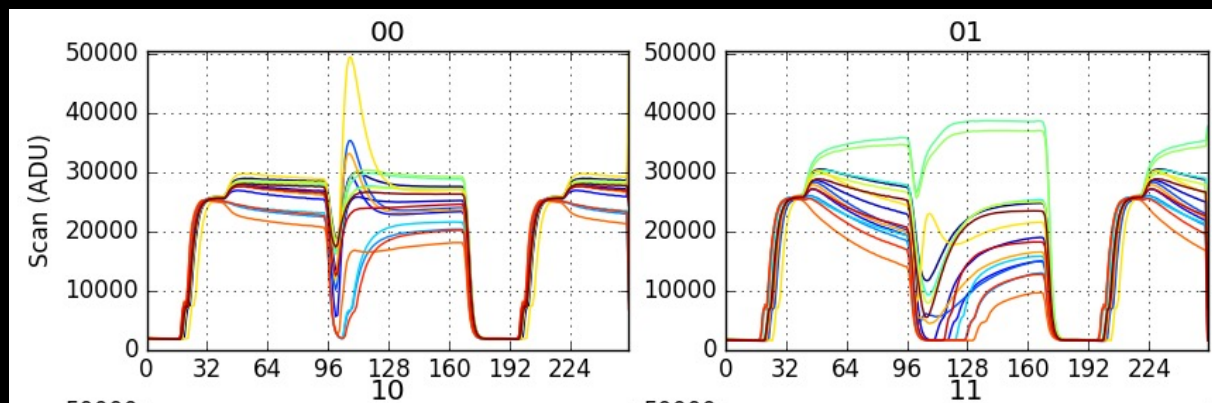
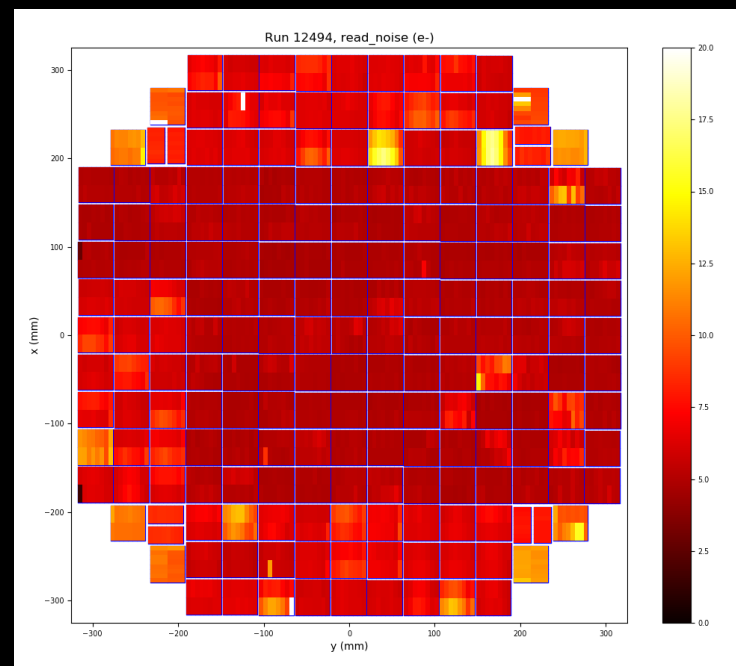
- e2v 'yellow corner': charge-like accumulation between readouts, depends on previous operation
- ITL: profile vs column (clocks)
  - Jumps in values, instability of profiles



# Clock injection in ITL CCDs



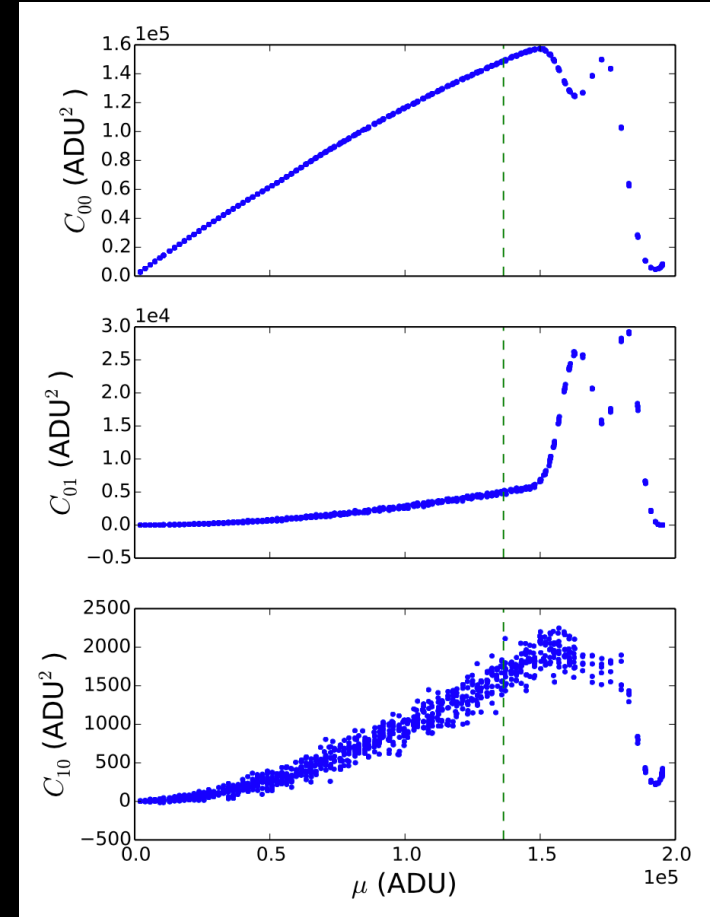
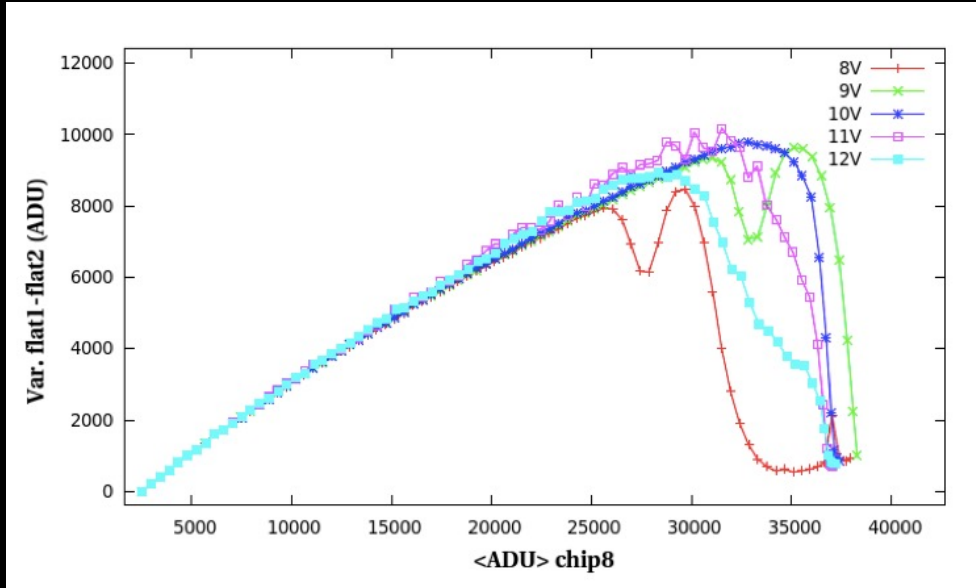
- Extra noise in raft tests
- Abnormal injection from serial clocks into output amplifiers
- Long settling times
- Selection of sensors: bias levels





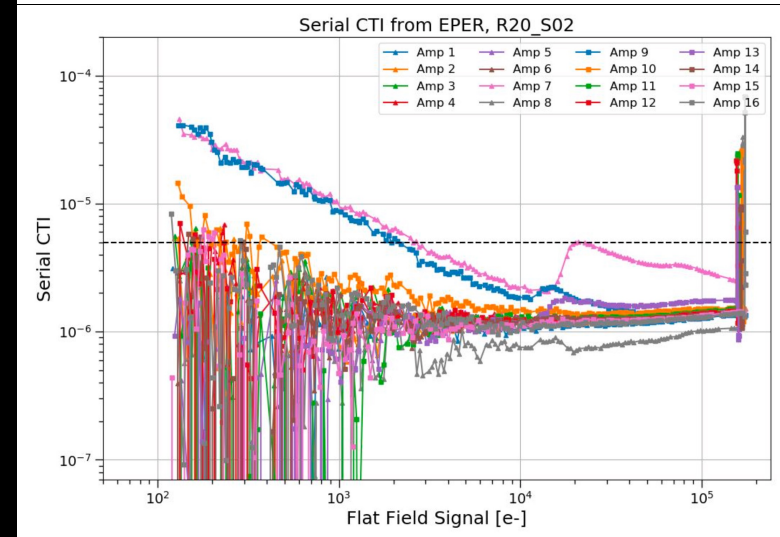
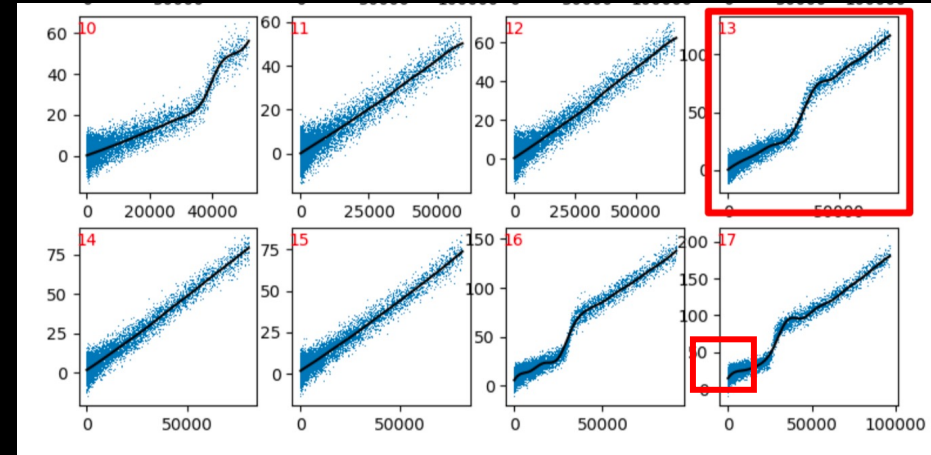
# Full well

- Photon Transfer Curve (variance of pair differences vs flux): gain, linearity, full well
- Various definition for full well
- Dependency on parallel clock levels, dips (see persistence)



# Transfer efficiency, traps, and pockets

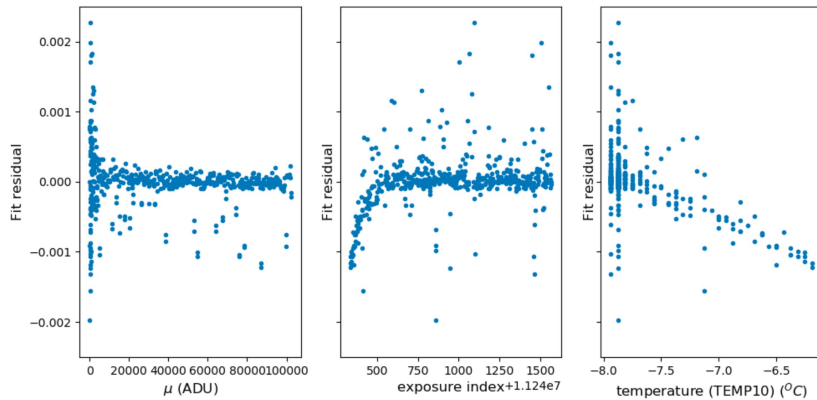
- Charge Transfer Efficiency
- Traps:
  - Seen at low flux (EPER)
  - Measurement of traps in frame with parallel transfer back-and-forth: issue with lifetime of traps
  - Traps in serial register ?
- Pockets (with threshold):
  - Dip of variance in the PTC
  - Parallel: due to transfer to serial register
  - Corner turn in serial register (e2v: fixed with bipolar mode)



ITL

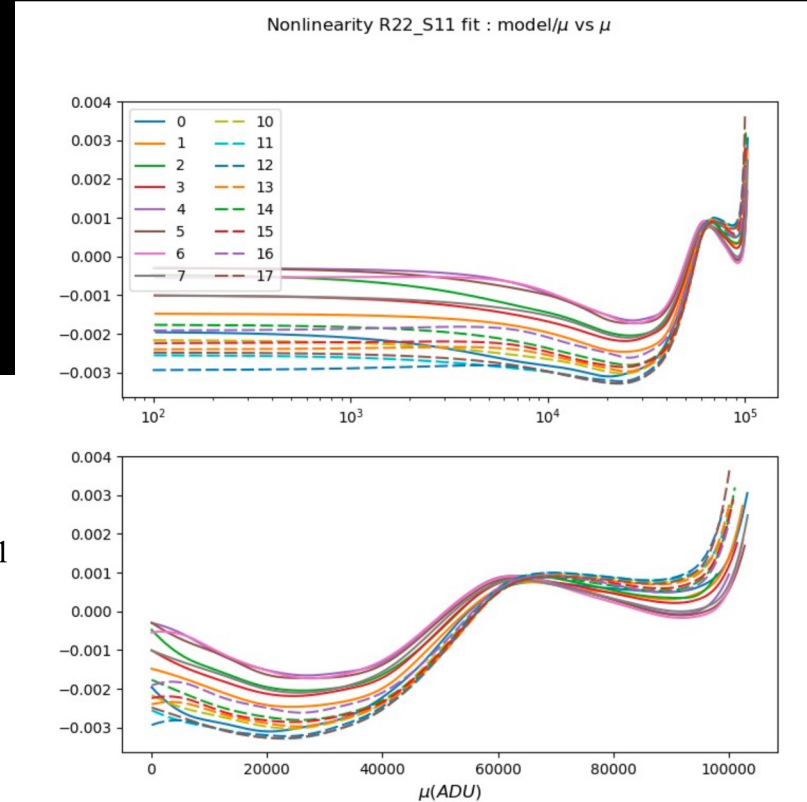
# Non-linearity and gain variations

- Non-linearity correction: common shape, per-channel, need for sufficient sampling and flux calibration
- Gain variation due to electronics temperature, limited with operating plan



R22\_S11  
C01

Residuals span more than 0.1% for a range of about 2 degrees C

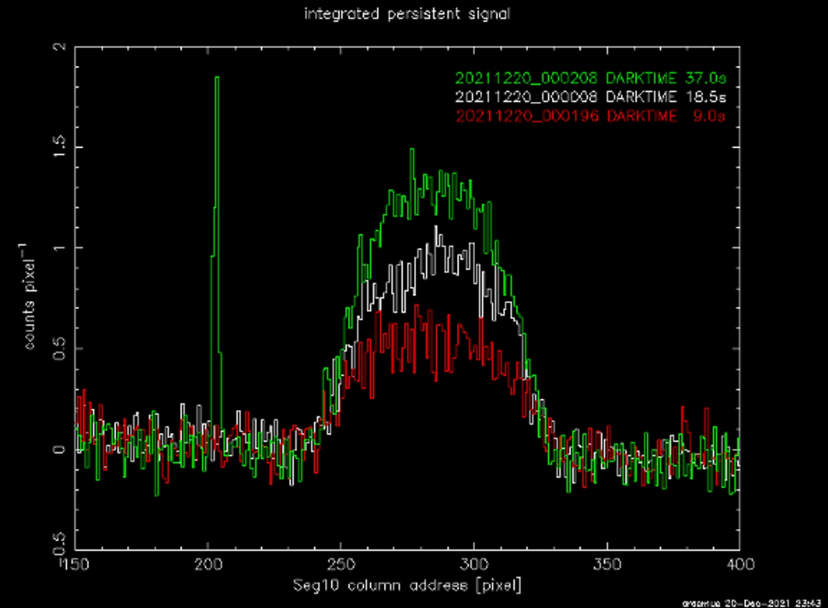
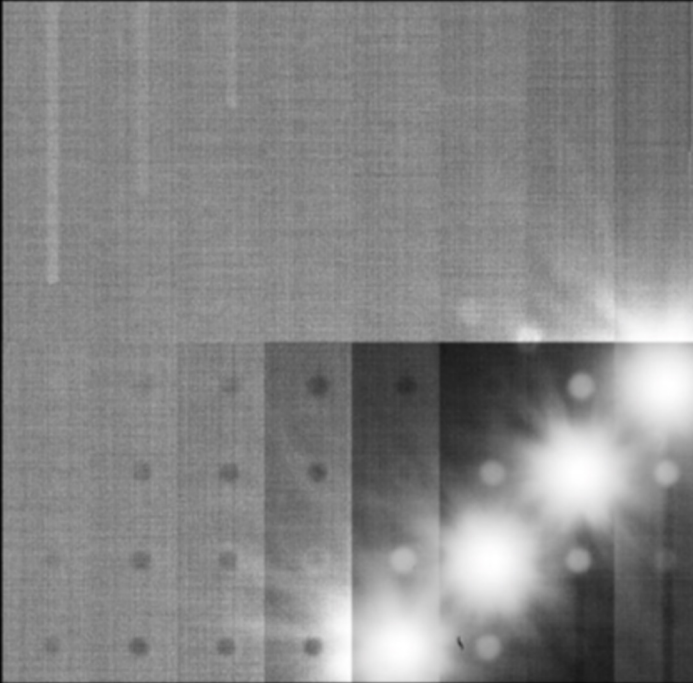


P. Astier

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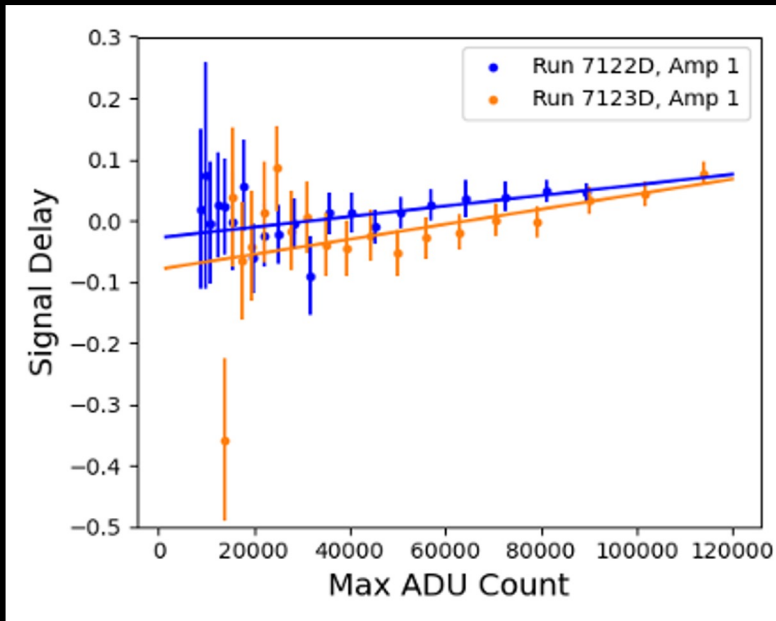
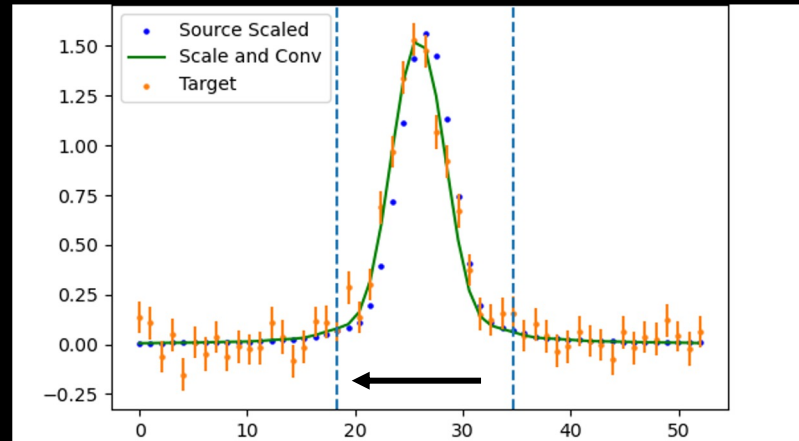
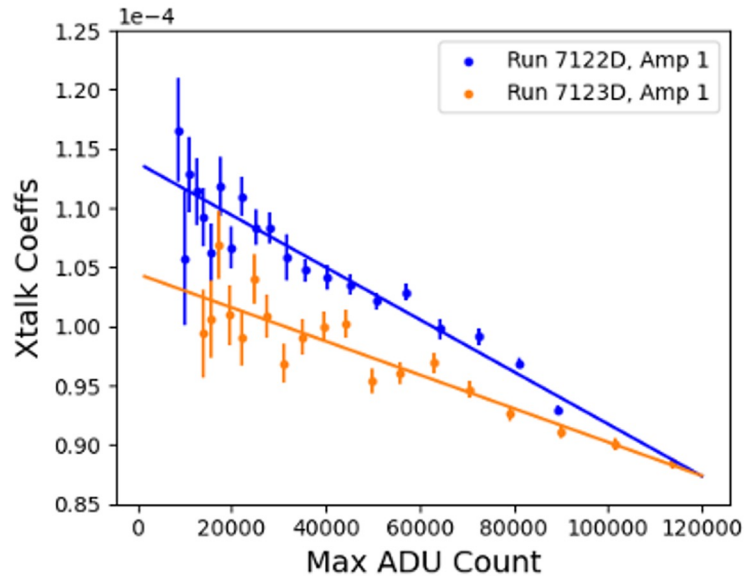
# Persistence

- Still investigating removal through operating change
- Long lifetime (several frames), dependency on operation sequence
- Also after saturated flat exposure



# Non-linear crosstalk

- More than a single matrix of coefficients
- Measurements of delay, non-linearity



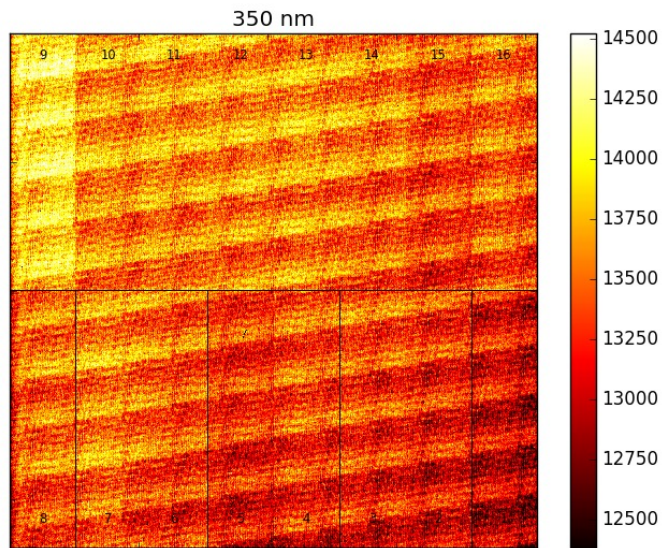
S. Liang  
A. Snyder



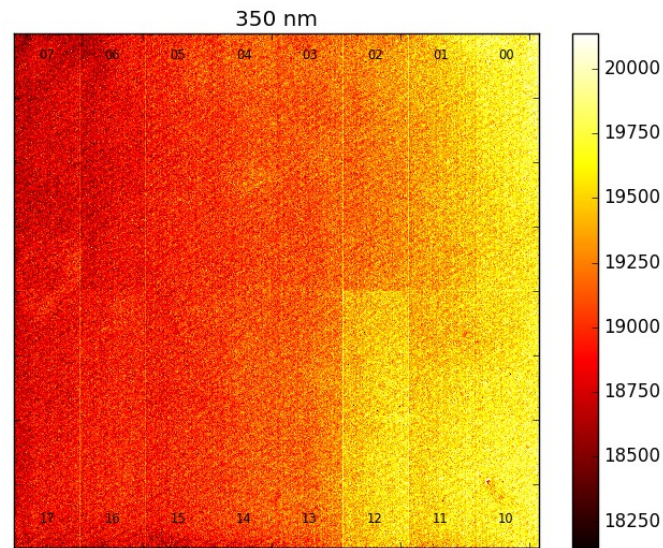
# Quantum Efficiency

- Quantum Efficiency, mapping of Photo-Response Non-Uniformity
- Processing effects on the back side
- Real QE non-uniformity vs other effects

e2v



ITL

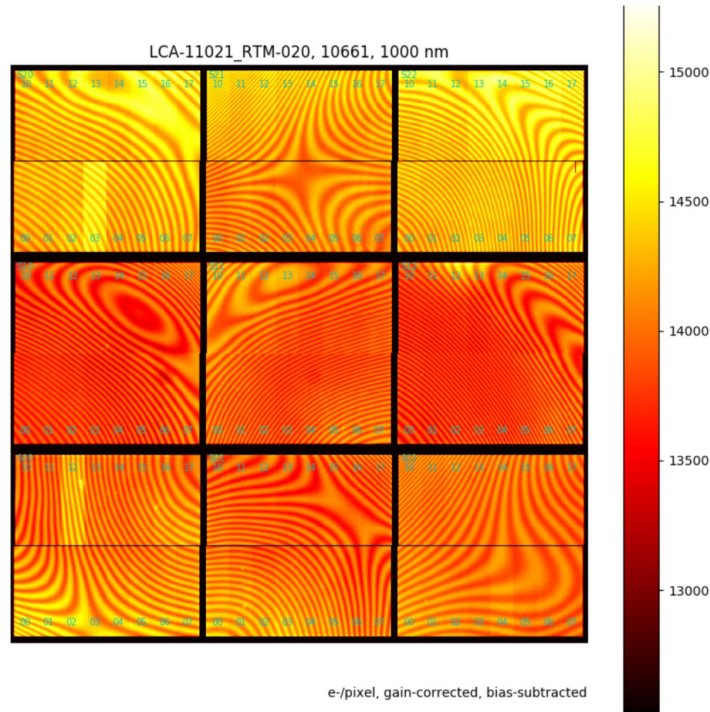


e-/pixel, gain-corrected, bias-subtracted

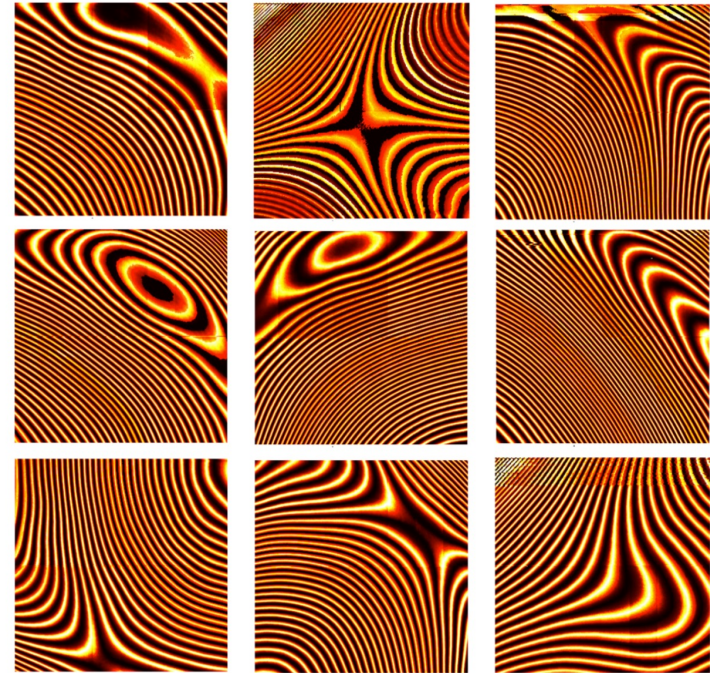
# Fringing in NIR

Fitting results on nine e2v sensors

SLAC TS8 DATA



Simulated fringing pattern



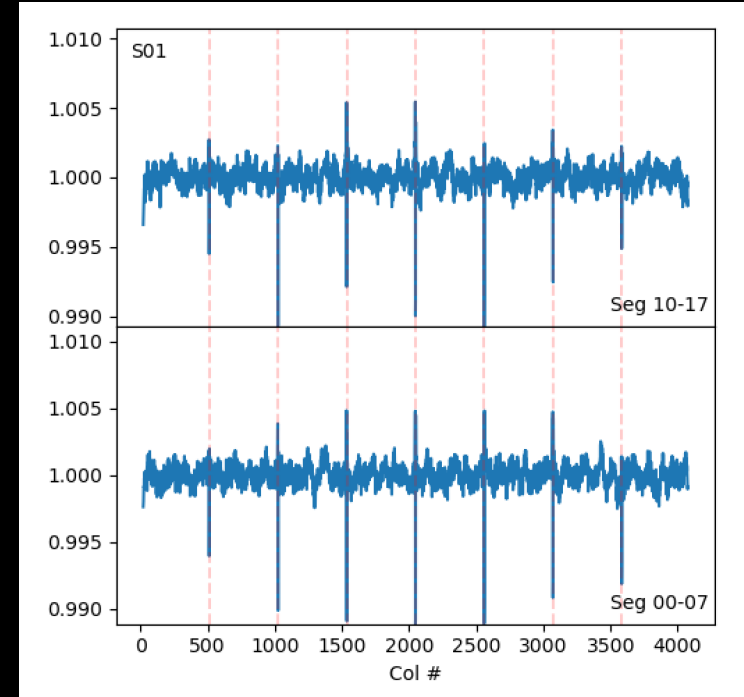
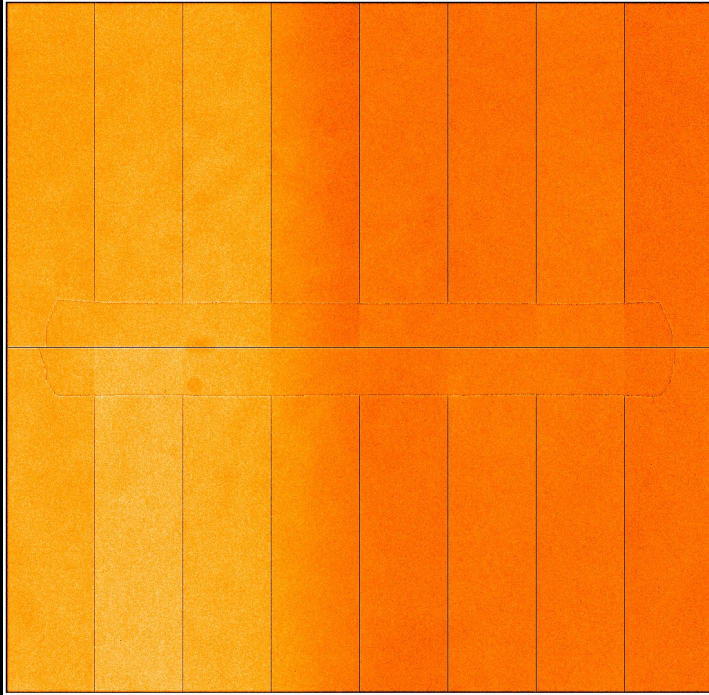
- Two interfaces on the 'front' side of the CCDs

Z. Guo

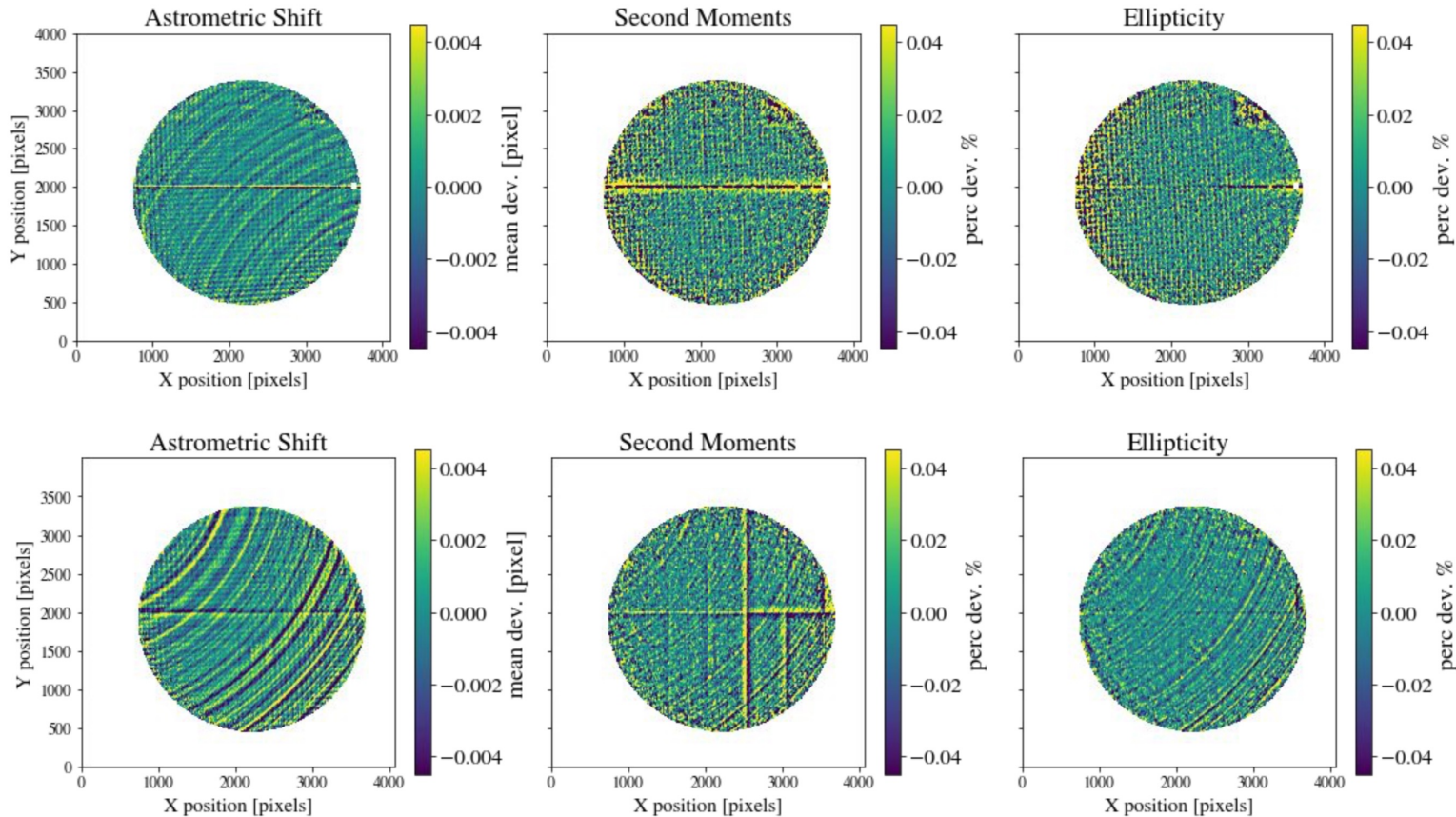


# Distortions at the edges

- Sensor edges, mid-line
- 'Divisadero' at the segment edges in e2v CCDs: non-uniform distribution of holes in the channel stops



# 'Tree rings' and other distortions



e2v

ITL

J. Esteves

- Measured with spot grid data on two sensors

